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PATENT  
Attorney Docket No. 5168-74

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of: )  
Kazuaki Yoshida ) Group Art Unit: To be Assigned  
Application No.: 10/593,147 ) Examiner: To be Assigned  
Filed: September 18, 2006 )  
For: Polishing Composition and ) Confirmation No.: To be Assigned  
Polishing Method )

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

**INFORMATION DISCLOSURE STATEMENT**

Enclosed for the consideration of the Examiner in connection with the prosecution of this case is a copy of six published Japanese patent applications and article set forth on the attached Form PTO/SB/08. Please refer to the abstracts in English for the relevance of each of the Japanese applications.

If there is any fee due in connection with the filing of this Statement, please charge such fee to our deposit account 06-0916.

Respectfully submitted,

FINNEGAN, HENDERSON, FARABOW,  
GARRETT & DUNNER, L.L.P.

Dated: December 14, 2006

By:   
Arthur S. Garrett  
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Complete if Known

DEC 14 2006

INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT

(Use as many sheets as necessary)

Application Number	10/593,147
Filing Date	September 18, 2006
First Named Inventor	Kazuaki Yoshida
Art Unit	To be Assigned
Examiner Name	To be Assigned

Sheet 1 of 2 Attorney Docket Number 5168-74



## U.S. PATENTS AND PUBLISHED U.S. PATENT APPLICATIONS

Examiner Initials	Cite No. <sup>1</sup>	Document Number	Issue or Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code <sup>2</sup> (if known)			
		US-			

Note: Submission of copies of U.S. Patents and published U.S. Patent Applications is not required.

## FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No. <sup>1</sup>	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	Translation <sup>6</sup>
		Country Code <sup>3</sup> Number <sup>4</sup> Kind Code <sup>5</sup> (if known)				
		JP 2000-8024	01-11-2000	Tanaka Hiroaki		X-Abstract
		JP 2001-93866	04-06-2001	Speedfam Co. Ltd.		X-Abstract
		JP 2004-203638	07-22-2004	Ube Nitto Kasei Co.; Tyemn Corp.		X-Abstract
		JP 2003-226865	08-15-2003	EKC Technology KK		X-Abstract
		JP 11-214338	08-06-1998	Memc KK		X-Abstract
		JP 11-60232	03-02-1999	ISO Mamoru		X-Abstract

## NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	Translation <sup>6</sup>
		U. MAHAJAN ET AL., "Dynamic Lateral Force Measurements during Chemical Mechanical Polishing of Silica," Electrochemical and Solid-State Letters, 2 (2) 80-82 (1999)	

Examiner Signature		Date Considered
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